

FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

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10/082,055

## LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

APPLICANT

Gotoh et al.

FILING DATE

February 26, 2002

GROUP

Not Assigned

## U.S. PATENT DOCUMENTS

EXAMINER		DOCUMENT NO.	DATE	NAME	CLASS	SUB-CLASS	FILING DATE
AM	AA	4,698,830	10/6/87	Barzilai et al.	377	19	
AM	AB	5,299,136	3/29/94	Babakanian et al.	364	488	
AM	AC	5,287,386	2/15/94	Wade et al.	375	36	
	AD						
	AE						
	AF						

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION		
							YES	NO	PART.
	AG								
	AH								
	AI								
	AJ								
	AK								
	AL								

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

AM	AM	"Integration of IEEE 1149.1 with Mixed ECL, TTL, and Differential Logic Signals", John Andrews, 1993 IEEE, pgs. 355-360.
AN	AN	"Built-In Parametric Test For Controlled Impedance I/Os", Tord Haulin, 1997 IEEE, pgs. 123-128.
AO	AO	

EXAMINER

DATE CONSIDERED

\*EXAMINER:

Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.